

Critical Scaling of Extended Power Law I-V Isotherms near Vortex Glass Transition

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In view of the question about the vortex glass theory of the freezing of disordered vortex matter raised by recent experimental observations we reinvestigate the critical scaling of high T_c superconductors. We find that dc current-voltage characteristic of mixed state superconductors has the general form of extended power law which is based on the Ginzburg-Landau (GL) functional in the similar way as the vortex glass theory. Isotherms simulated from this nonlinear equation fit the experimental I-V data of Strachan et al.[Phys.Rev.Lett. 87, 067007 (2001)]. The puzzling question of the derivative plot for the I-V curves and the controversy surrounding the values of critical exponents are also discussed.

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The hypothesis of a vortex glass in disordered high temperature superconductors[1] has spurred much research and many discussions during more than one decade and continued to be a very controversial issue[2, 3]. Though the striking dc current-voltage(I-V) data collapse shown by Koch et al.[4], and found by other groups on other samples, strongly supports the consensus that a glass transition occurs in high-temperature superconductors(HTS)[5], this widely accepted evidence has met serious doubt recently. Strachan et al. show wide range accurate isothermal I-V measurements over 5 or 6 decades on a high quality 2200 Å thick $YBa_2Cu_3O_{7-\delta}$ film with $T_c \approx 91.5K$ and transition width about 0.5K[3] and find although the I-V isotherms measured in a magnetic field can be collapsed onto scaling functions proposed by Fisher et al.[1] as is widely reported in the literature, these excellent data collapse can also be achieved for a wide range of exponents and glass temperatures T_g as demonstrated in their Fig.2(a),2(b) and 2(c)[3]. Since the critical temperature T_g cannot be determined uniquely, they argued that necessary evidence for a vortex-glass transition to zero resistance is still not seen in their I-V experimental data, as well as in all the ones they know of in the literature which scale. Therefore, the correctness of the vortex glass picture has to be reinvestigated. In this work, we try to settle this remarkable controversy by introducing a general extended power law form of the current-voltage isotherms.

In analogue with the vortex glass theory [1], our extended power law equation is also based on the GL free energy functional of a system of N flux lines with a field H along the z direction in a sample length L which can be described with the free energy represented by the trajectories $\{\vec{r}_j(z)\}$ of these flux lines and the pinning potential $V_P(\vec{r})$ arising from inhomogeneities and defects in sample [1, 5, 6, 7] as

$$F = \frac{1}{2}\varepsilon_l \sum_{j=1}^N \int_0^L \left| \frac{d\vec{r}_j(z)}{dz} \right|^2 dz + \frac{1}{2} \sum_{i \neq j} \int_0^L V(r_{ij}) dz + \sum_{j=1}^N \int_0^L V_P[\vec{r}_j(z)] dz \quad (1)$$

Here $V(r_{ij}) = V(|\vec{r}_i - \vec{r}_j|) = 2\varepsilon_0 K_0(r_{ij}/\lambda_{ab})$ is the interaction potential between lines with in-plane London penetration depth λ_{ab} and $K_0(x)$ is the modified Bessel function $K_0(x) \approx (\pi/2x)^{1/2} e^{-x}$. ε_l is the linear tension of flux line and $\varepsilon_0 \approx (\Phi_0/4\pi\lambda_{ab})^2$ is the energy scale for the interaction.

Thermally activated flux motion can be considered as the sequence of thermally activated jumps of the vortex segments or vortex bundles between the metastable states generated by disorder. Every elementary jump is viewed as the nucleation of a vortex loop, and the mean velocity of the vortex system is determined by the nucleation rate [1, 7]

$$v \propto \exp(-\delta F/kT) \quad (2)$$

Here δF is the free energy for the formation of the critical size loop or nucleus which can be found by means of the standard variational procedure from the free energy functional due to the in-plane displacement $\vec{u}(z)$ of the moving vortex during loop formation

$$F_{loop}[\vec{u}] = \int dz \left[\frac{1}{2}\varepsilon_l \left| \frac{d\vec{u}(z)}{dz} \right|^2 + V_P(\vec{u}(z)) - \vec{f}_s \cdot \vec{u} \right] \quad (3)$$

with

$$\vec{f}_s = \vec{f}_L + \vec{f}_\eta = \frac{J_P \Phi_0}{c} \times \vec{e}_z \quad \text{and} \quad J_P = J - \frac{E}{\rho_f} \quad (4)$$

where $f_L = \vec{J} \times \vec{e}_z/c$ is the Lorentz force due to applied current J and f_η is the viscous drag force on vortex, $f_\eta = -\eta v_{vortex}$, with $v_{vortex} = d\vec{u}/dt$ and viscous drag coefficient $\eta \approx (\Phi_0 B_{c2})/(\rho_n c^2)$ as estimated by Bardeen and Stephen [8].

There are two essential differences between our equations (1) and (3) and the corresponding ones used in previous vortex glass theories:

(i) We considered both the Lorentz force $\vec{f}_L$ and the viscous drag force $\vec{f}_\eta$ on the vortex loop during its formation while in present vortex glass theories only bare Lorentz force $\vec{f}_L$ has been taken into account[1, 5, 7].

(ii) The effect of the real sample size L on the current-voltage response is explicitly estimated in our case. The influence of the finite size effects on the I-V isotherms is recently revealed even in thickest films at zero magnetic field[9].

These two factors result in a new form for the I-V isotherms of superconducting vortex matter.

In stead of the barrier energy found by the vortex glass model[1] as

$$\delta F = U(J) \approx U_c \left(\frac{J_c}{J} \right)^\mu \quad (5)$$

now we have the barrier energy

$$\delta F = U(J_p) \approx U_c \left(\frac{J_c}{J_p} \right)^\mu \quad (6)$$

which implies a current-voltage characteristic of the form

$$E(J) = \rho_f J \exp \left[-\frac{U_c}{kT} \left(\frac{J_c}{J_p} \right)^\mu \right] \quad (7)$$

where U_c is a temperature- and field-dependent characteristic pinning energy related to the stiffness coefficient and J_c is a characteristic current density related to U_c , μ is an numerical exponent.

Considering the real size effect Eq.(7) leads to a general normalized form of the current-voltage characteristic [10] in the form

$$y = x \exp [-\gamma (1 + y - x)^p] \quad (8)$$

where

$$\gamma = \frac{U_c}{kT} \left(\frac{J_c}{J_L} \right), \quad x = \frac{J}{J_L}, \quad y = \frac{E(J)}{\rho_f J_L}, \quad p = \mu$$

with J_L the transport current density corresponding to the case where the critical size of loop formation is equal to the real sample size L . The ρ_f in Eq.(7) is the flux flow resistance of a pinning free mixed state as derived by Bardeen and Stephen. Its relation with the normal resistance is of the form

$$\frac{\rho_f}{\rho_n} = \frac{2\pi a^2 B}{\Phi_0} = \left(\frac{a}{\xi} \right)^2 \frac{B}{B_{c2}} \approx \frac{B}{B_{c2}} \quad (9)$$

In an earlier work [11], equation(8) has also been shown in connection with the Anderson-Kim model. Compared with the widely used power law nonlinear response $E \propto J^n$ (see Ref.5), equation(8) can also be nearly equivalently expressed in an extended power law form

$$\frac{y}{x} = e^{-\gamma} (x - y + 1)^{n-1} \quad (10)$$

with n a numerical factor depending on the parameters γ and p in Eq.(8), which can be determined from solving the equation

$$\frac{y_i}{x_i} = e^{-\gamma} (x_i - y_i + 1)^{n-1} \quad (11)$$

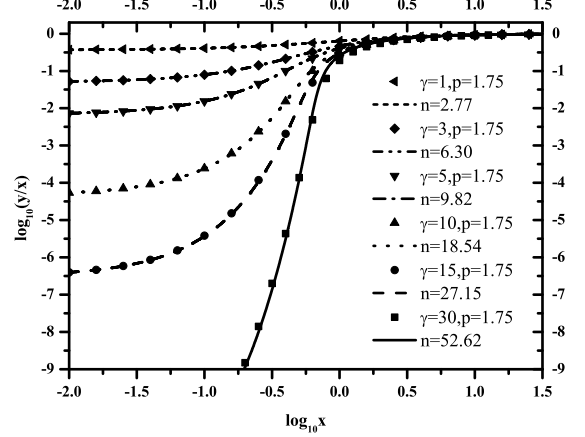


FIG. 1: Comparison of solutions of Eq.(8)(solid symbols) and Eq.(10)(curves).

where the subscript i denote the corresponding values at the inflection point of $\ln y \sim \ln x$ curve for Eq.(8) with the maximum derivative S_{max} so

$$\frac{\partial^2 \ln y}{\partial^2 \ln x} \Big|_{x=x_i} = 0 \quad \text{and} \quad S_{max} = \frac{\partial \ln y}{\partial \ln x} \Big|_{x=x_i}$$

In Fig.1 we show the numerical solutions of Eq.(8) and Eq.(10) for comparison.

The complex experimental current-voltage data are usually described phenomenologically with a form[5]

$$E(J) = J \rho_f(T, B, J) = J \rho_f e^{-U_{eff}(T, B, J)/kT} \quad (12)$$

Equation(8) implies that effective barrier can be explicitly expressed as

$$U_{eff}(T, B, J) = U_c(B, T) F[J/J_c(B, T)] \quad (13)$$

with $J_c(B, T) = J_L(B, T)$.

Incorporating it into the commonly observed scaling behavior of magnetic hysteresis $M(H)$ in superconductors, it can be shown that $U_c(B, T)$ and $J_c(B, T)$ in Eq.(13) must take the following forms[5]

$$\begin{aligned} U_c(B, T) &= \Psi(T) B^n \propto [T^*(B) - T]^\delta B^n \\ J_c(B, T) &= \lambda(T) B^m \propto [T^*(B) - T]^\alpha B^m \end{aligned} \quad (14)$$

with $T^*(B)$ being the irreversibility temperature where tilt modules and stiffness of vortex matter vanish. Considering $\rho_f \propto T$, one finds from Eq.(8) the following temperature dependent relations for γ and $I - V$ isotherms of optimally doped YBCO samples in a given magnetic field as

$$\begin{aligned} \gamma(T) &= \gamma_0 (T^* - T)^\delta / kT \\ I &\propto x J_L(T) \propto x (T^* - T)^\alpha \\ V &\propto y J_L(T) \rho_f \propto y (T^* - T)^\alpha T \end{aligned} \quad (15)$$

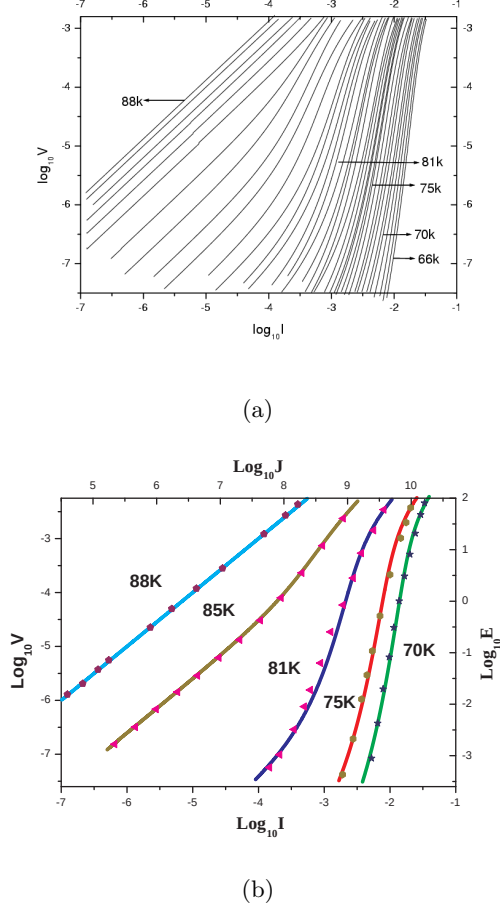


FIG. 2: Comparison of simulated $I-V$ isotherms from Eqs.(8) and (15) with the experimental data of Ref.3[Phys.Rev.Lett.87, 067007(2001)].

(a) $I-V$ isotherms simulated from the extended power law equations (8) and (15) with assumed $T^*(B = 4T) = 88K$, and $\alpha = 3.0, \delta = 1.5, p = 1.75$ and $\gamma_0 = 3.21 \times 10^{21}$.
 (b)Comparison of our simulated $I-V$ isotherms(lines) with the experimental data of Ref.3(solid symbols).

Combination of equations (8) and (15) enables us to simulate the experimentally measured $I - V$ isotherms of Strachan et al.[3] as shown in Fig.2, where the parameters used in (8) and (15) are $\alpha = 3.0, \delta = 0.5, p = 1.75, \gamma_0 = 3.21 \times 10^{21}$ and the irreversibility temperature $T^*(B = 4T)$ is assumed $88K$ similar to the Fig.1 in Ref.[3]. On the basis of nearly 100 simulated $I - V$ isotherms from $68K$ to $88K$ with temperature intervals of $0.2K$, we obtain three different scaling data collapse analyses with assumed critical temperature T_g of $81K, 75K$ and $70K$ respectively. In Fig.3 we show the comparison of our result with the data collapses of measured $I - V$ curves of Strachan et al. in Ref.[3] and find fair agreement.

In Fig.3 of the Ref.[3] another serious puzzle is mentioned with plotting the derivatives of the $\ln V$ vs $\ln I$ for

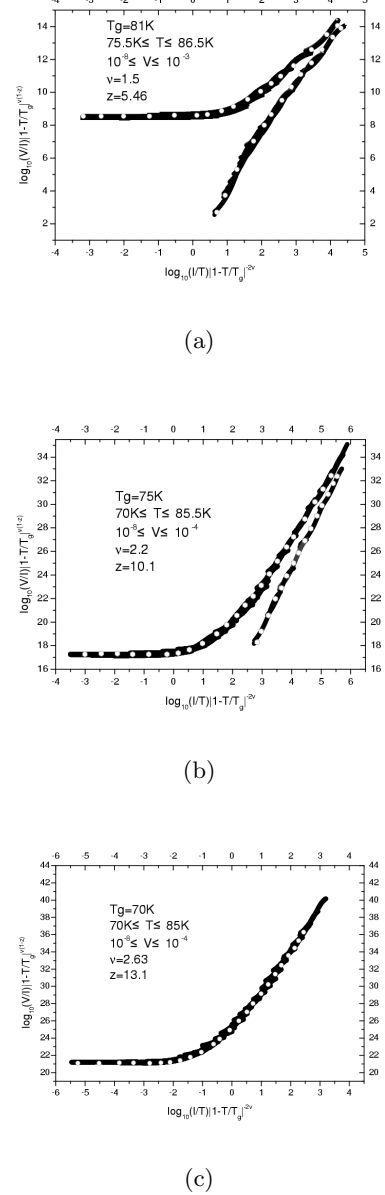


FIG. 3: •: Collapse of the simulated $I-V$ isotherms in Fig.2(a) using various critical parameters compared with o: the experimental $I-V$ isotherms for a $2200\text{\AA}$ YBCO film in $4T$ measured by Strachan et al.[3]. The conventional analysis is shown in (a).

experimental isotherms following Repaci et al.[12]. All isotherms seem to have a maximum slope at about some current with Ohmic tails developing to the left of the peaks. This behavior is inconsistent with the scaling function of vortex-glass transition[4] which should predict a horizontal line in the $[d\ln V/d\ln I]_T \sim \ln I$ plot at $T = T_g$. Nevertheless, our extended power law $I - V$ equations may give it a reasonable explanation.

In Fig.4 we plot the slope of experimental $I - V$

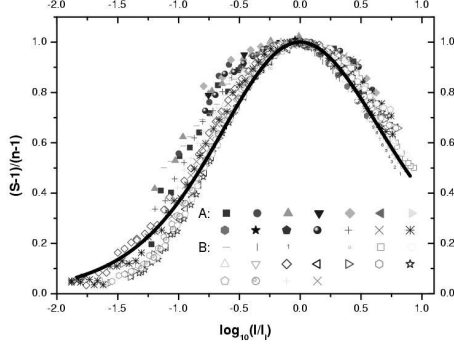


FIG. 4: Empirical scaling of the derivatives of the experimental $\ln V \sim \ln I$ isotherms. A: data from Ref.12 B: data from Ref.3. The solid curve is the results simulated from Eq.(17).

isotherms of Ref.[3] and [12] in an empirical scaling form

$$\frac{S-1}{n-1} = \Phi(I/I_i) \quad (16)$$

and find that these experimental data are collapsed, where the subscript i denotes the value at inflection point of $\ln V \sim \ln I$ curve, $S \equiv [d\ln V/d\ln I]_T$ and n denotes S_{max} at inflection. This empirical scaling function can be derived from extended power law nonlinear I-V isotherms. Starting from our equation (8) one finds analytic equation

$$\frac{S-1}{n-1} = C \frac{(x-y) \ln(x/y)}{1+y-x+yp \ln(x/y)} \quad (17)$$

where

$$C = \frac{1+y_i-x_i+y_i p \ln(x_i/y_i)}{(x_i-y_i) \ln(x_i/y_i)} \quad (18)$$

shown by the solid curve in Fig.4.

The agreement of the simulated I-V isotherms derived from Eqs.(8) and (15) with the wide-range experimental data of Ref.[3] as shown in our Fig.2,3 and 4 demonstrates that extended power law is the general form of I-V isotherms. Though, in principle, each I-V curve can have both positive and negative curvature parts joined at the inflection point, the actually used current-voltage window in measurements limits the observable part of each I-V isotherms and results in the previous reasonable scaling analysis [1, 2]. Using wider I-V windows of measurements, Strachan et al. find that non-Ohmic-power-law-like behavior can be fit to all $T < 81K$ isotherms over at least four decades of voltage data and thus insightfully reveal that the conventional I-V scaling cannot determine a unique T_g with corresponding critical exponents. The successful reproduce of their experimental data collapses with our simulated I-V isotherms from equations (8) and (15) with the uniquely assumed parameters the irreversibility temperature $T^*(B = 4T) = 88K$ and $\alpha = 3.0$, $\delta = 0.5$, $p = 1.75$, $\gamma_0 = 3.21 \times 10^{21}$ shows that extended power law is helpful in settling the controversy surrounding critical phenomena in high temperature superconductors.

In conclusion, we show that dc current-voltage characteristic of mixed state superconductors has the general form of extended power law. Isotherms simulated from this nonlinear equation fit the recent experimental I-V data of Strachan et al. This equation also gives a reasonable explanation to the critical scaling relation recently observed in the derivatives of the $\ln V$ vs $\ln I$.

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